APR 3 0 2002

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application Serial No.	
Eiling Date	
Assignee	Micron Technology, Inc.
Group Art Unit	
Examiner	Ml22-1637
Title: Semiconductor Processing Methods Of Forming Processing Methods Of Forming Dynamic Random Related Integrated Circuitry	

## **INFORMATION DISCLOSURE STATEMENT**

Reference - - See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the reference listed on the attached Form PTO-1449. No admission is made regarding whether the submitted reference is prior art.

Citation of this reference is respectfully requested.

Respectfully submitted,

Date:

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Reg. No. 36,138

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	AR	S. Wolf, Silicon Pro	cessing for the V	/LSI Era , Ve	olume 3 - The Submicro	on MOSFET, ©1995 Lat	tice Press, pa	iges 330, 331	, 366 and 367.		
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.											